



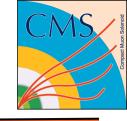
Measurements of Radiation Damage in the CMS Pixel Detector with the First Few Inverse Femtobarns

Seth Zenz On behalf of CMS Pixels

19th RD50 Workshop 23 November 2011

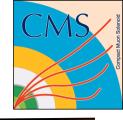




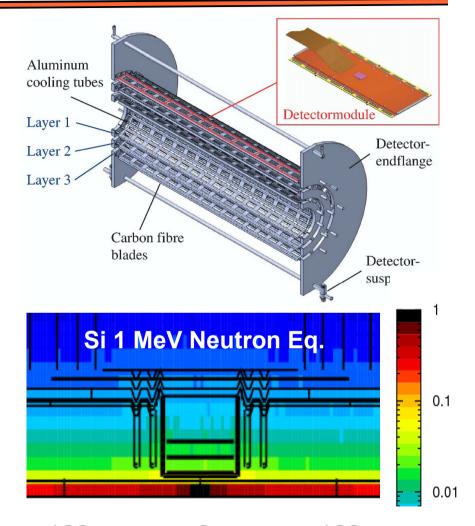


- Brief Introduction to the CMS Pixel Detector
- Measurement Conventions
- Leakage Current Measurements
 - vs. Time (model comparison)
 - vs. Luminosity
 - vs. Fluence
 - vs. Detector Phi
 - Temperature Scaling: Bulk and Surface (?) Current
- Depletion Voltage Measurements
 - vs. Time (model comparison)





- Three barrel layers:
 - 4.3, 7.2, 10.8 cm
 - 48M pixels, 0.78 m²
- 2x2 disks
 - 18M pixels, 0.28 m²
- This talk: focus on barrel for simplicity
- 2011 operating temperature: 17.2 °C



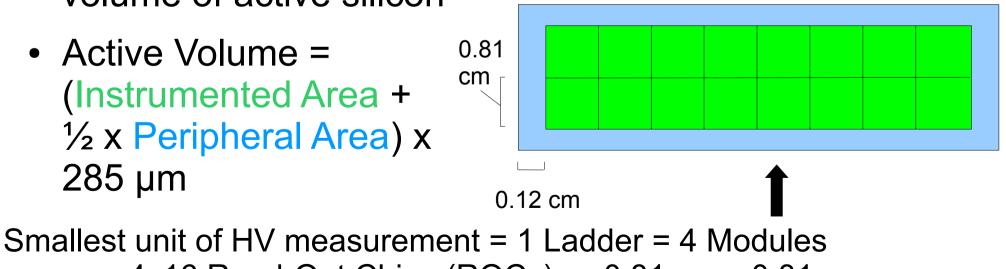
-100 0 100 Smallest unit of HV measurement = 1 Ladder \rightarrow [-30,0] and [0,30] cm



- Following the guidelines of the *Inter-Experiment* Working Group on Radiation Damage in Silicon Detectors . . .
- Current is corrected to 0 °C

$$I\left(T_{ref}\right) = I(T).\left(\frac{T_{ref}}{T}\right)^2 .exp\left(-\frac{E_g}{2k_B}\left[\frac{1}{T_{ref}} - \frac{1}{T}\right]\right),$$

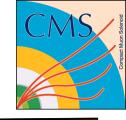
- Current is measured in µA/cm³, normalized to the volume of active silicon
- Active Volume = (Instrumented Area + ¹/₂ x Peripheral Area) x 285 µm



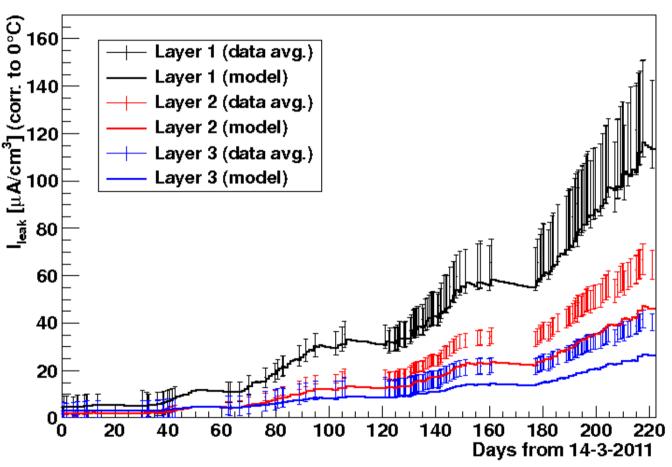
= 4x16 Read-Out Chips (ROCs) \rightarrow 0.81 cm x 0.81 cm



During 2011 leak



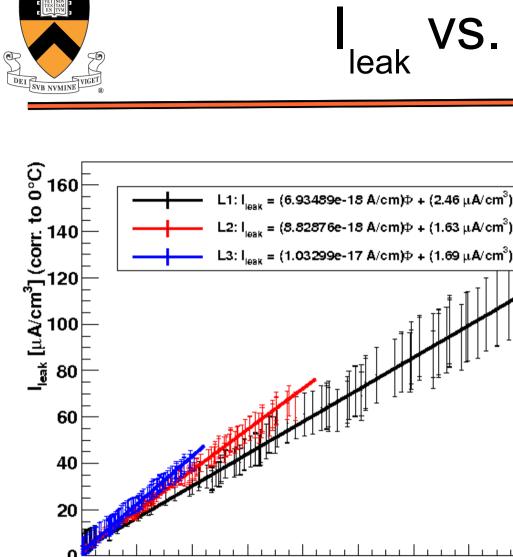
- Midpoint: mean over entire layer
- Errors bars: RMS deviation
- Model comparison: See talk by C. Barth, this session
- Model uses
 z = 0, mean r



- Fair agreement for Layer 1
- Factor of ~2 for Layers 2 and 3



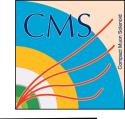
vs. Fluence leak



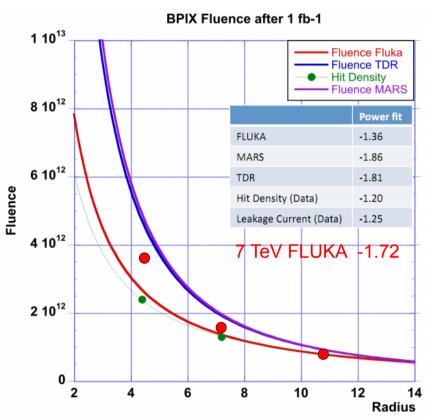
- L3: I_{μesk} = (1.03299e-17 A/cm)⊅ + (1.69 μA/cm³) I_{leak} /Vol. = $\alpha \Phi$ ×10¹² 12 10 14 16 6 8 18 20 Fluence Φ [1 MeV Neutron Eq. / cm²] Fit "measures" α as a consistency check...
- $\alpha(20^{\circ}C) \sim 4e-17 \text{ A/cm} \rightarrow \alpha(0^{\circ}C) \sim 6e-18 \text{ A/cm}$

2

Data-model Inconsistencies



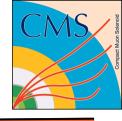
- Culprit could be...
 - Fluence?
 - Wide range of predictions
 - Using hit density instead of 7 TeV FLUKA → all three layers would disagree as much as L3 currently does!
 - Model?
 - α is too well known to allow disagreemnt seen in simple I vs. Fluence fit
 - Assorted 10% effects: zdependence, r-dependence ionization current, ...?



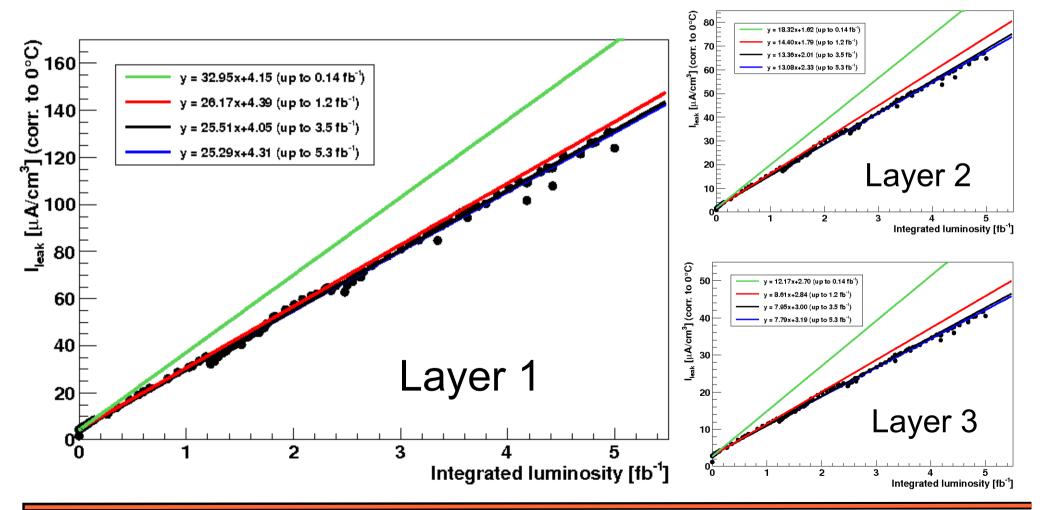
Red Points: 7 TeV Fluka (+ Radial Interpolation) Red Line: scaled 14 TeV Fluka Hit density measurement: O(600 MeV) pions dominate These have a 1 MeV neutron equivalence ~ 1



vs. Luminosity leak



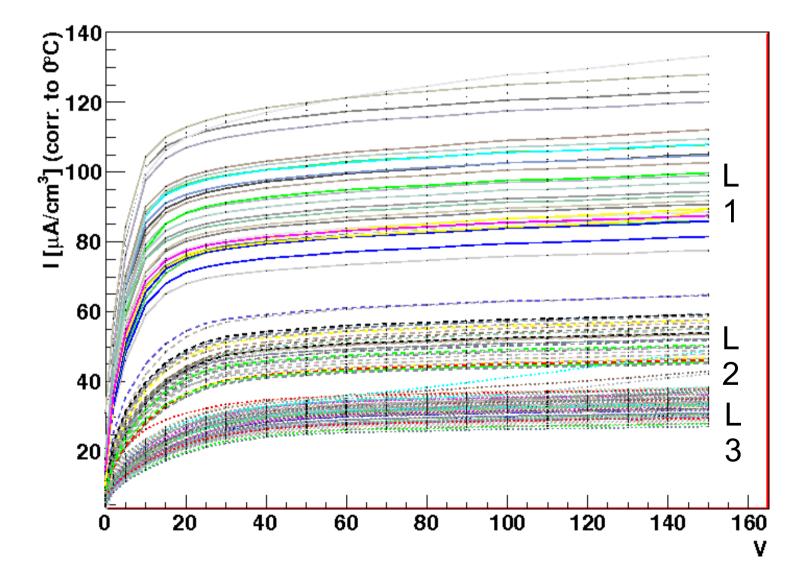
- Detector operations: most interested in extrapolation vs. lumi
- I_{leak} exceeds power supply and readout capabilities at ~750 fb⁻¹

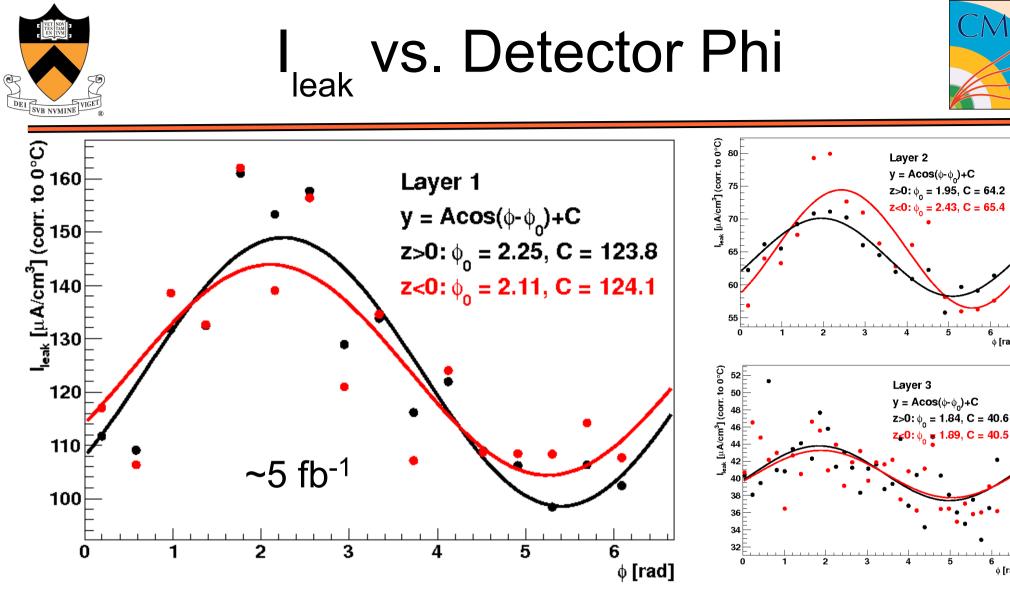




IV Curves





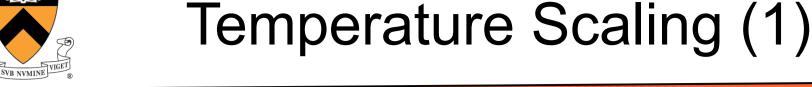


- LHC Beam Spot is not at center of Pixel Detector!
- Known to be at $(x,y) = (-2.4mm, 3.9mm) \rightarrow \phi \sim 2.12$ •
- 30% effect on potential Layer 1 lifetime! •
- Can also see impact of staggered geometry

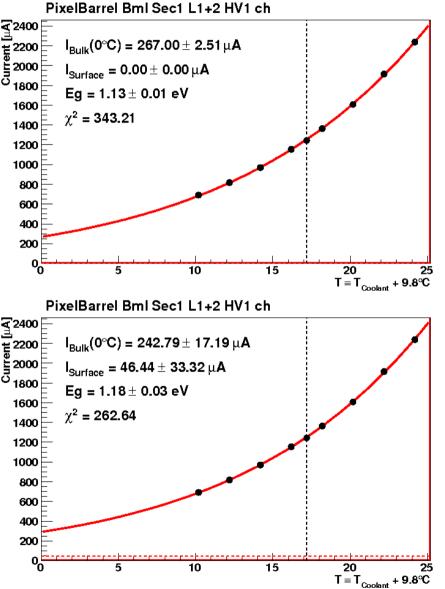
• [rad]

{[rad]

11

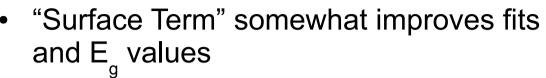


- Investigate Temperature scaling of I_{leak} by fitting scans
- Let effective band gap E₂ vary (should be 1.21 eV)
- Try allowing T-independent surface term - should correspond to ohmic behavior in IV curve after saturation
 - Following LHCb talk (P. Collins) at 1st LHC Rad. Dmg. IEWG mtg
- Long extrapolation (17.2 °C operation temperature to 0 $^{\circ}C) \rightarrow significant impact$

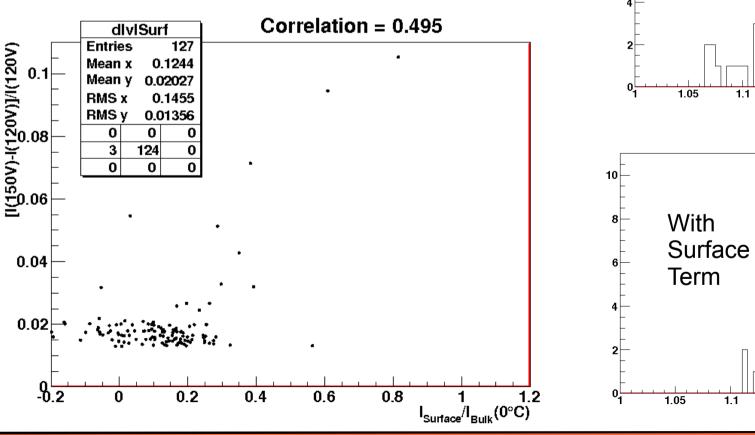


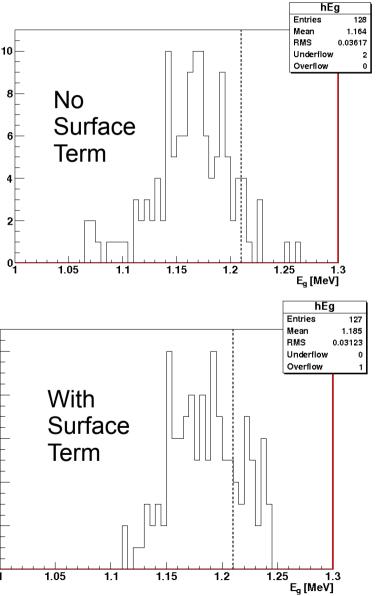


Temperature Scaling (2)



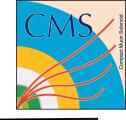
- Few channels show correlation b/w Tindependent term and "Ohmic behavior"
- So this term not used elsewhere in talk



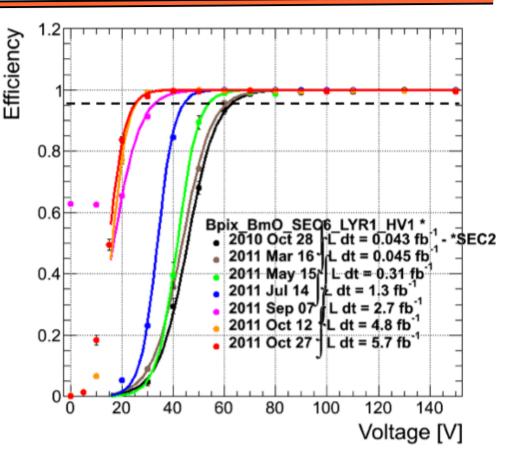




' dep from Hit Efficiency

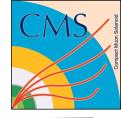


- Reduce voltage of selected channel during operation and observe impact on hit efficiency
- Take voltage corresponding to 95% hit efficiency V₉₅ ~ V_{dep}

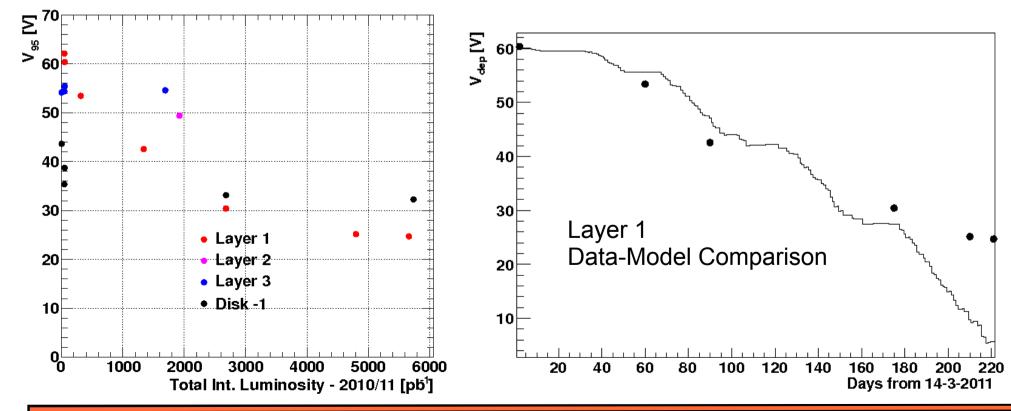


 Very preliminary work (not shown today) fitting cluster charge vs. voltage: agrees qualitatively with this method





- Compared to calculations with same model as I comparison
- Good agreement up to the last part of the year, with divergence at end of run as model \rightarrow 0V
- Follow through "type inversion" next year critical operational question is how voltage will *increase* as compared with models





Conclusions



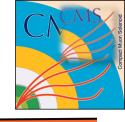
- No big surprises so far
- Many small improvements to be studied:
 - Channel-by-channel temperature
 - Position: average over ladders in z, add disks and average in r, improve model grid radial interpolation
 - Reconcile hit density with fluence models
 - Finalize depletion voltage from Landau curves
- Questions for experts
 - Comments on model-data agreement?
 - Best temperature for shutdown? On or off?
 - Suggestions for new or improved measurements?
- We are in early days yet!

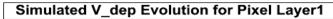


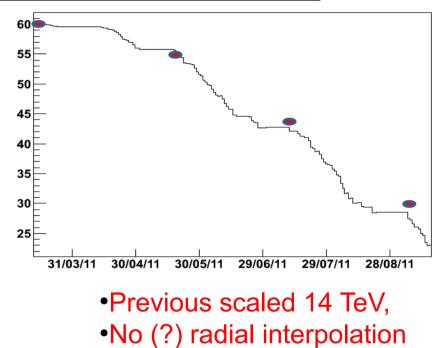


Extras

Old Vdep Plot







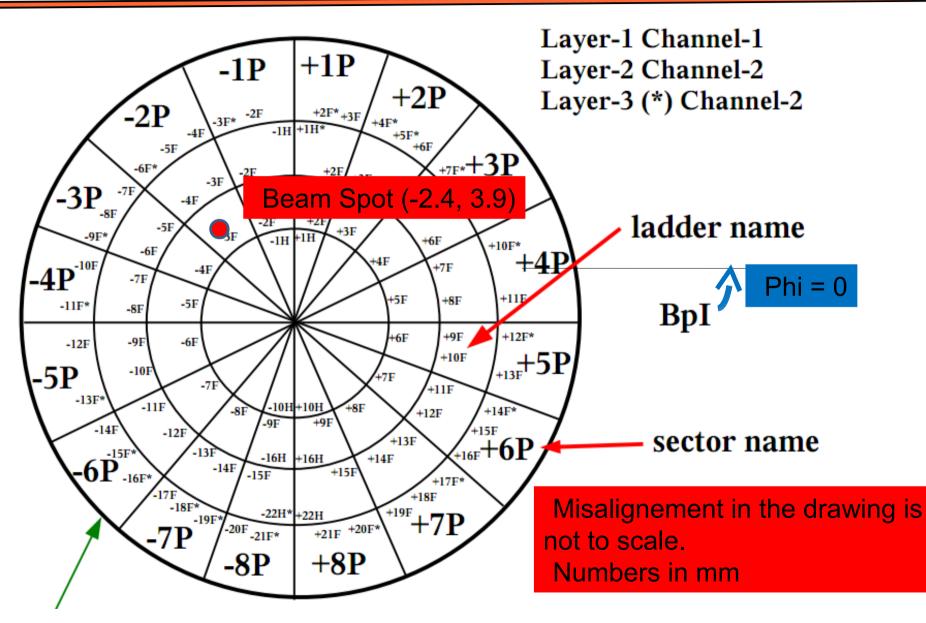
DEI

VIGE

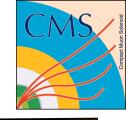
SVB NVMINE

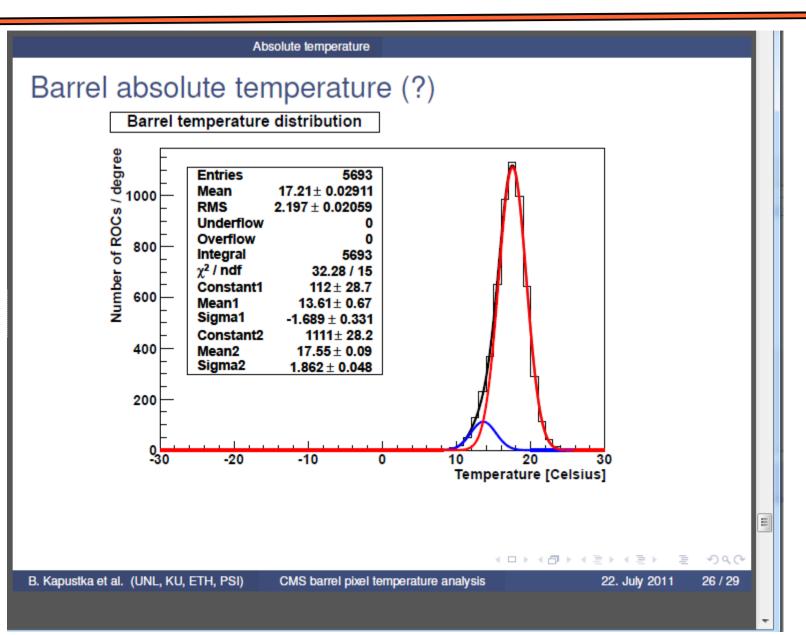








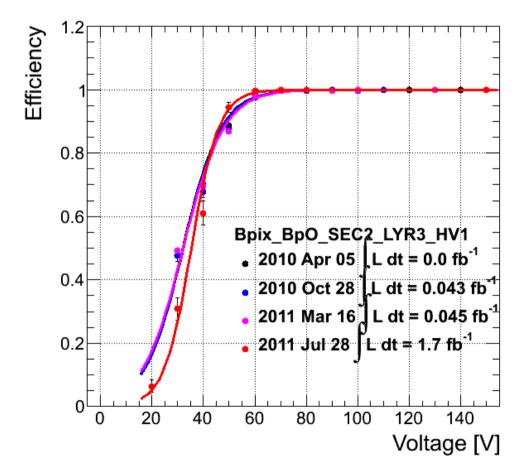




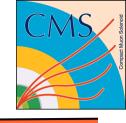


Layer 3 $V_{_{95}}$









Parameters used for Simulation

• Leakage Current: $I = \alpha \phi V$ Time independent but temperature dependent term not clear in T-changing environment. Interpretation to be a "instantaneous" annealing effect -> max T of corresponding annealing time taken (?)

with α = 1.23e-17 A/cm exp (-t₁/ τ_1)exp(-t₂/ τ_1)... + -8.9e-17 A/cm + 4.6 AK/cm e-14/T + 3.07e-18 A/cm ln(t/t₀)

and 1/ $_1$ = 1.2e13 exp(-1.12/2k_BT) *(60*60*24) 1/day

• Temperature scaling: $(T_1/T_2)^2 \exp(-1.12/2k_B (1/T_1 - 1/T_2))$ C. Barth also started simulations with E=1.21eV according to Technical Note by A.Chilingarov





Parameters used for Simulation

All orange highlighted values are taken from measurements • Full depletion voltage: (-> Ph.D. Thesis A. Dierlamm $N_{eff} = N_{\Delta} + N_{C} + N_{V}$ 2003) with: $N_A = g_a \exp(-t_1/g) \exp(-t_2/g)...$ $N_{c} = 0.9 |N_{eff0}| *$ $(1 - \exp(-10.9e-2/|N_{eff}|) + g_{c})$ $N_{y} = -g_{y}$ (1 - 1/(1+t_1/y) 1/(1+t_2/y)...) and $g_a = 1.81e-2 1/cm$, $g_y = 5.16e-2 1/cm$, C. Barth $g_{c}=1.6e-2 1/cm$ $_{a} = 1/(2.3e13 \exp(-1.08/k_{B}T))$ $_{v} = 1/(1.5e15 \exp(-1.33/k_{B}T))$